

# Resource Summary Report

Generated by [NIF](#) on Sep 9, 2026

## Rigaku: AZX 400

RRID:SCR\_020439

Type: Tool

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### Proper Citation

Rigaku: AZX 400 (RRID:SCR\_020439)

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### Resource Information

**URL:** <https://www.rigaku.com/products/semi/azx400>

**Proper Citation:** Rigaku: AZX 400 (RRID:SCR\_020439)

**Description:** Sequential wavelength dispersive XRF spectrometer for large samples film thickness and composition measurements on large and heavy samples, wafers, and media disks.

**Resource Type:** instrument resource

**Keywords:** Rigaku, Spectrometer, Instrument, Equipment, USEdit,

**Availability:** Commercially available

**Resource Name:** Rigaku: AZX 400

**Resource ID:** SCR\_020439

**Alternate IDs:** Model\_Number\_AZX 400

**Record Creation Time:** 20220129T080350+0000

**Record Last Update:** 20260905T132916+0000

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### Ratings and Alerts

No rating or validation information has been found for Rigaku: AZX 400.

No alerts have been found for Rigaku: AZX 400.

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### Data and Source Information

**Source:** [SciCrunch Registry](#)

## Usage and Citation Metrics

We have not found any literature mentions for this resource.